

LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)

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APPLICATION NO

10:076.296

APPLICANT

Conant et al.

FILING DATE

February 13, 2002

GROUP

1765

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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
					YES NO

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AKS	Conant et al., "Cyclic Fatigue Testing of Surface-Micromachined Thermal Actuators", 1998 ASME International Mechanical Engineering Congress and Exposition, Nov. 15-20, 1998, Anaheim, CA DSC-Vol. 66, pp. 273-277
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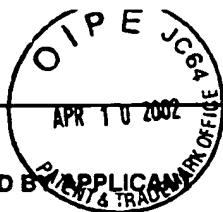
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Anita K. Stambor

DATE CONSIDERED

12/15/03

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APPLY NUMBER 9840-0068-999	APPLY DATE 10/076.296
APPLICANT Conant et al.	
EXAMINER February 13, 2002	DR. # 1765 To be assigned

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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	EXAMINER APPROPRIATE
AFV	AA 6,201,629	3/13/01	McClelland et al.			
	AB 5,959,760	9/28/99	Yamada et al.			

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DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
AC PCT/US01/15514	5/14/01	PCT Int'l Search Report			YES NO

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